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Diagnosis in Analog Electronic Circuits, Electrical Power Systems and Smart Grids

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Deadline for manuscript submissions:

closed (30 March 2022)

Message from the Guest Editors

Dear Colleagues,

This Special Issue will promote advancement in the following topics related to the diagnosis of analog electronic circuits, electrical power systems, and smart grids:

- Parametric fault diagnosis in analog circuits;
- Catastrophic fault diagnosis in analog circuits;
- Testability, solvability, and ambiguity group determination in lumped circuits;
- Smart metering and soft computing techniques applied to the fault diagnosis;
- Diagnosis and prognosis techniques in electrical power systems;
- Smart grids: maintenance, fault prevention, fault resolution, fault-tolerant approach;
- Smart grids: non-intrusive monitoring techniques;
- CAD and simulation techniques oriented to analog circuits fault diagnosis

We welcome your contribution.











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Message from the Editor-in-Chief

Electronics is a multidisciplinary journal designed to appeal to a diverse audience of research scientists, practitioners, and developers in academia and industry. The journal is devoted to fast publication of latest technological breakthroughs, cutting-edge developments, and timely reviews of current and emerging technologies related to the broad field of electronics. Experimental and theoretical results are published as regular peer-reviewed articles or as articles within Special Issues guest-edited by leading experts in selected topics of interest.

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